

Attorney Docket No.: 0553-0401

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| T 4                   | 1: 4: 6.                             | \  |
|-----------------------|--------------------------------------|--|
| In re Application of: |                                      | I hereby certify that this correspondence is being deposited   |
|                       | Yoshifumi TANADA                     | with the United States Postal Service as first class mail in an envelope addressed to: the Commissioner for Patents, |
| Serial l              | No.: 10/807,692                      | P.O. Box 1450, Alexandria, VA 22313-1450 on  |
| Filed:                | March 24, 2004                       | ) (Date of Deposit)  |
|                       |                                      | Shannon Wallace  |
| For:                  | Circuit For Inspecting Semiconductor | Name of applicant, assignee, or Registered Rep.  |
|                       | Device And Inspecting Method         | I Sharron Mallace (0/13/06)  |
| Exami                 | ner: Vibol Tan                       | Signature Date   |
|                       |                                      | )  |
| Art Un                | it: 2819                             | )  |

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

## **AMENDMENT E**

In response to Office Action of March 14, 2006, please amend the above-identified application as follows: